

Test methods for electrical materials, printed board and other interconnection structures and assemblies - Part 5-503: General test method for materials and assemblies - Conductive anodic filaments (CAF) testing of circuit boards

EESTI STANDARDI EESSÕNA

NATIONAL FOREWORD

See Eesti standard EVS-EN 61189-5-503:2017 sisaldab Euroopa standardi EN 61189-5-503:2017 ingliskeelset teksti.	This Estonian standard EVS-EN 61189-5-503:2017 consists of the English text of the European standard EN 61189-5-503:2017.
Standard on jõustunud sellekohase teate avaldamisega EVS Teatajas	This standard has been endorsed with a notification published in the official bulletin of the Estonian Centre for Standardisation.
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English Version

Test methods for electrical materials, printed board and other
interconnection structures and assemblies - Part 5-503: General
test method for materials and assemblies - Conductive anodic
filaments (CAF) testing of circuit boards
(IEC 61189-5-503:2017)

Méthodes d'essai pour les matériaux électriques, les cartes
imprimées et autres structures d'interconnexion et
ensembles - Partie 5-503 : Méthodes d'essai générales
pour les matériaux et les assemblages - Essais des
filaments anodiques conducteurs (CAF) des cartes à circuit
imprimé
(IEC 61189-5-503:2017)

Prüfverfahren für Elektromaterialien, Leiterplatten und
andere Verbindungsstrukturen und Baugruppen - Teil 5-
503: Allgemeine Prüfverfahren für Materialien und
Baugruppen - Leitfähige anodische Fasern (CAF), Prüfung
für Leiterplatten
(IEC 61189-5-503:2017)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

European foreword

The text of document 91/1433/FDIS, future edition 1 of IEC 61189-5-503, prepared by IEC/TC 91 "Electronics assembly technology" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 61189-5-503:2017.

The following dates are fixed:

- latest date by which the document has to be (dop) 2018-03-26
implemented at national level by
publication of an identical national
standard or by endorsement
- latest date by which the national (dow) 2020-06-26
standards conflicting with the
document have to be withdrawn

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Endorsement notice

The text of the International Standard IEC 61189-5-503:2017 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 60068-3-4	NOTE	Harmonized as EN 60068-3-4.
IEC 60068-3-5	NOTE	Harmonized as EN 60068-3-5.
IEC 60721-1	NOTE	Harmonized as EN 60721-1.
IEC 60721-2-1	NOTE	Harmonized as EN 60721-2-1.
IEC 60721-3-0	NOTE	Harmonized as EN 60721-3-0.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60068-1	2013	Environmental testing -- Part 1: General and guidance	EN 60068-1	2014
IEC 60068-2-30	-	Environmental testing -- Part 2-30: Tests - Test Db: Damp heat, cyclic (12 h + 12 h cycle)	EN 60068-2-30	-
IEC 60068-2-38	-	Environmental testing -- Part 2-38: Tests - Test Z/AD: Composite temperature/humidity cyclic test	EN 60068-2-38	-
IEC 60068-2-66	-	Environmental testing -- Part 2-66: Test methods - Test Cx: Damp heat, steady state (unsaturated pressurized vapour)	EN 60068-2-66	-
IEC 60068-2-67	-	Environmental testing -- Part 2: Tests - Test Cy: Damp heat, steady state, accelerated test primarily intended for components	EN 60068-2-67	-
IEC 60068-2-78	-	Environmental testing -- Part 2-78: Tests - Test Cab: Damp heat, steady state	EN 60068-2-78	-
IEC 60194	-	Printed board design, manufacture and assembly - Terms and definitions	-	-
IPC-TM-650 No 2.6.14.1	-	Electrochemical Migration Resistance Test	-	-
IPC-TM-650 No 2.6.25	-	Conductive Anodic Filament (CAF) Resistance Test: X-Y Axis	-	-

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